



RADIO TEST REPORT

Test Report No. : 31HE0085-HO-01-D-R1

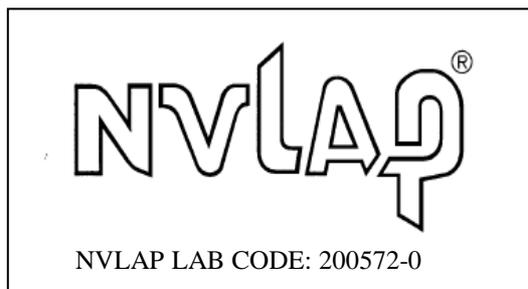
Applicant : Sony Computer Entertainment Inc.
Type of Equipment : Computer Entertainment System
Model No. : CECH-3001A
CECH-3001B
FCC ID : AK8CBEH18C1
Test regulation : FCC Part 15 Subpart C: 2010
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This report is a revised version of 31HE0085-HO-01-D. 31HE0085-HO-01-D is replaced with this report.

Date of test: March 11 to 23, 2011

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This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
<http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

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SECTION 1: Customer information

Company Name	Sony Computer Entertainment Inc.
Brand Name	SONY
Address	1-7-1 Konan, Minato-ku, Tokyo 108-0075, Japan
Telephone Number	+81-3-6748-6333
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Contact Person	Akiko Tsukada

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment	Computer Entertainment System	
Model No	CECH-3001A CECH-3001B	
Serial No	CECH-3001A	1200222 (Power Supply: DELTA) 1200223 (Power Supply: DELTA)
	CECH-3001B	1200218 (Power Supply: SONY)
Rating	AC120V / 60Hz	
Country of Manufacture	JAPAN/CHINA	
Receipt Date of Sample	March 10, 2011	
Condition of EUT	Production prototype (Not for Sale: This sample is equivalent to mass-produced items.)	
Modification of EUT	No modification by the test lab.	

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2.2 Product Description

Models: CECH-3001A and CECH-3001B, referred to as the EUT in this report, is a Computer Entertainment System. The EUT contains Bluetooth (Ver. 2.0+EDR) module and IEEE802.11b/g WLAN module. Those modules do not transmit simultaneously.
The difference between CECH-3001A and CECH-3001B is HDD type.

List of Model No.:

Model No.	Product Name	Note
CECH-3001A	Computer Entertainment System (PlayStation3)	Tested model
CECH-3001B	Computer Entertainment System (PlayStation3)	Tested model
DECH-3000A	Debugging Station (PlayStation3)	#1
DECH-S3000A	Debugging Station (PlayStation3)	#1

Note:

#1 - DECH-3000A/DECH-S3000A are same as the tested model CECH-3001A except model names for different intended purpose.

The clock frequencies used in the EUT: Max clock frequency is 3.2GHz.

Bluetooth (Ver. 2.0+EDR)

Equipment Type	Transceiver
Frequency of Operation	2402-2480MHz
Type of Modulation	FHSS (GFSK, $\pi/4$ -DQPSK, 8DPSK)
Bandwidth & Channel spacing	1MHz & 1MHz
Power Supply (inner)	DC3.3V/1.8V
Antenna Type	PIFA
Antenna Gain	2.5 dBi (max)
Antenna Connector Type	U.FL

IEEE802.11b/g WLAN

Equipment Type	Transceiver	
Frequency of Operation	2412-2462MHz	
Type of Modulation	DSSS/OFDM	
Bandwidth & Channel spacing	20MHz & 5MHz	
Power Supply (inner)	DC3.3V/1.8V	
Antenna Type	Antenna 0: IFA	Antenna 1: PIFA
Antenna Gain	Antenna 0: 4.3 dBi (max)	Antenna 1: 2.5 dBi (max)
Antenna Connector Type	Antenna 0: N/A	Antenna 1: U.FL

For IEEE802.11b/g WLAN part, please see UL Japan, Inc. Test Report Number: 31HE0085-HO-01-C-R1.

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2010, final revised on December 6, 2010 and effective January 5, 2011

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.247 Operation within the bands 902-928MHz,
2400-2483.5MHz, and 5725-5850MHz

* The EUT complies with FCC Part 15 Subpart B: 2010, final revised on December 6, 2010.

3.2 Procedures and results

Item	Test Procedure	Specification	Worst Margin	Results	Remarks	
Conducted Emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements IC: RSS-Gen 7.2.4	FCC: Section 15.207 ----- IC: RSS-Gen 7.2.4	QP 8.7dB, 0.15000MHz, N (BT, Tx 2402MHz, DH5/3DH5) AV 11.7dB 0.37988MHz, N 0.37998MHz, L (BT, Tx, 2402MHz, DH5) 0.38020MHz, N 0.37972MHz, L (BT, Tx, 2402MHz, 3DH5)	Complied	-	
Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) ----- IC: RSS-210 A8.1 (b)	See data.	Complied	Conducted	
20dB Bandwidth	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) ----- IC: RSS-210 A8.1 (a)		-	Conducted	
Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) ----- IC: RSS-210 A8.1 (d)		Complied	Conducted	
Dwell time	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) ----- IC: RSS-210 A8.1 (d)		Complied	Conducted	
Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.8	FCC: Section15.247(a)(b)(1) ----- IC: RSS-210 A8.4 (2)		Complied	Conducted	
Spurious Emission & Band Edge Compliance	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.9	FCC: Section15.247(d) ----- IC: RSS-210 A8.5 RSS-Gen 6 and 7.2.3		7.4dB 105.008MHz, QP, Vert.	Complied	Conducted/ Radiated

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

FCC 15.31 (e)

This EUT provides stable voltage(DC3.3/1.8V) constantly to RF part regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	-	Conducted

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	3.1dB
No.2	3.3dB
No.3	3.7dB
No.4	3.2dB

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	3.5dB	5.1dB	5.2dB	4.8dB	5.1dB	4.4dB	4.3dB
No.2	4.0dB	5.1dB	5.2dB	4.8dB	5.0dB	4.3dB	4.2dB
No.3	4.2dB	4.7dB	5.2dB	4.8dB	5.0dB	4.5dB	4.2dB
No.4	4.0dB	5.0dB	5.1dB	4.8dB	5.0dB	5.1dB	4.2dB

*3m/1m/0.5m = Measurement distance

Power meter (+dB)	
Below 1GHz	Above 1GHz
1.0dB	1.0dB

Antenna terminal conducted emission and Power density (+dB)			Antenna terminal conducted emission (+dB)		Channel power (+dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz	
1.0dB	1.1dB	2.7dB	3.2dB	3.3dB	1.5dB

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9
Inquiry

Details of Operating Mode(s)

Test Item	Mode	Tested model	Tested frequency
Conducted Emission *1)	Tx (Hopping off) DH5, 3DH5	CECH-3001A CECH-3001B	2402MHz 2441MHz 2480MHz
Spurious Emission (Radiated)	Tx (Hopping off) DH5, 3DH5	CECH-3001B	2402MHz 2441MHz *2) 2480MHz
	Tx (Hopping off) DH5	CECH-3001A	2441MHz *2)
Spurious Emission (Conducted)	Tx (Hopping off) DH5, 3DH5	CECH-3001A	2402MHz 2441MHz 2480MHz
Carrier Frequency Separation	Tx (Hopping on) DH5, 3DH5 Inquiry	CECH-3001A	2402MHz 2441MHz 2480MHz
20dB Bandwidth	Tx (Hopping off) DH5, 3DH5 Inquiry	CECH-3001A	2402MHz 2441MHz 2480MHz
Number of Hopping Frequency	Tx (Hopping on) DH5, 3DH5 Inquiry	CECH-3001A	-
Dwell time	Tx (Hopping on), -DH1, DH3, DH5 -3DH1, 3DH3, 3DH5 Inquiry	CECH-3001A	-
Maximum Peak Output Power	Tx (Hopping off) DH5, 3DH5 Inquiry	CECH-3001A	2402MHz 2441MHz 2480MHz
Band Edge Compliance (Conducted)	Tx DH5, 3DH5 -Hopping on -Hopping off	CECH-3001A	2402MHz 2480MHz
99% Occupied Bandwidth	Tx DH5, 3DH5 -Hopping on -Hopping off	CECH-3001A	2402MHz 2441MHz 2480MHz

*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)

*EUT has the power settings by the software as follows;

Power settings: Same as production model

Software/Version: LABTOOL_LV2DIAG_20100402_for_356

*This setting of software is the worst case.

Any conditions under the normal use do not exceed the condition of setting.

In addition, end users cannot change the settings of the output power of the product.

Antenna has two kinds of manufacturer's antennas (TYCO and HITACHI) and the test was performed only with TYCO antenna according to the customer's request, because these have similar antenna characteristics and equal maximum gain.

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*1) The test was performed for both of CECH-3001A(Power Supply: DELTA) and CECH-3001B(Power Supply: SONY). Radiated Spurious Emission was performed with CECH-3001B(Power Supply: SONY) as a representative.

*2) The difference between CECH-3001A(Power Supply: DELTA) and CECH-3001B(Power Supply: SONY) was confirmed by Bluetooth DH5 2441MHz Transmitting (Tx) mode.

4.2 Configuration and peripherals

This page has been submitted for a separate exhibit.

This page has been submitted for a separate exhibit.

SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber . The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector	: QP and AV
Measurement range	: 0.15-30MHz
Test data	: APPENDIX
Test result	: Pass

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SECTION 6: Radiated Spurious Emission

Test Procedure

EUT was placed on a urethane platform of nominal size, 1.5m by 1.0m, raised 0.8m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

In any 100kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20dBc was applied to the frequency over the limit of FCC 15.209 / Table 5 of RSS-Gen 7.2.5 (IC) and outside the restricted band of FCC15.205 / Table 3 of RSS-Gen 7.2.2 (IC).

Frequency	Below 1GHz	Above 1GHz		20dBc
Instrument used	Test Receiver	Spectrum Analyzer		Spectrum Analyzer
Detector	QP	PK	AV	PK
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz VBW: 3MHz	RBW: 1MHz VBW: 10Hz or RBW: 1MHz VBW: 270Hz *1)	RBW: 100kHz VBW: 300kHz (S/A)
Test Distance	3m	3m (below 10GHz), 1m*2) (above 10GHz),		3m (below 10GHz), 1m*2) (above 10GHz),

*1) Used for the band edge of the carrier and the harmonics that can be measured. The VBW is based on the inverse of the duty cycle (see Appendix).

*2) Distance Factor: $20 \times \log(3.0\text{m}/1.0\text{m}) = 9.5\text{dB}$

- The carrier level and noise levels were confirmed at each position of X and Y axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 30M-25GHz
Test data : APPENDIX
Test result : Pass

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SECTION 7: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	3MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3MHz	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	1MHz	3MHz	As necessary capture the entire dwell time per hopping channel	Peak	Clear Write	Spectrum Analyzer
Conducted Spurious Emission*	9kHz to 150kHz	200Hz	620Hz	Auto	Peak	Max Hold	Spectrum Analyzer
	150kHz to 30MHz	10kHz	30kHz				
	30MHz to 25GHz (Less or equal to 5GHz)	100kHz	300kHz				
Conducted Spurious Emission Band Edge compliance	20MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer

*In the frequency range below 30MHz, RBW was narrowed to separate the noise contents. Then, wide-band noise near the limit was checked separately, however the noise was not detected as shown in the chart. (9kHz-150kHz:RBW=200Hz, 150kHz-30MHz:RBW=10kHz)

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : APPENDIX
Test result : Pass